


<b>Search Notes</b>  	<b>Application/Control No.</b>  10663730	<b>Applicant(s)/Patent Under Reexamination</b>  NOTO ET AL.
	<b>Examiner</b>  Chawan, Sheela C	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	152,154,254,285,312, 252,270	12/26/06	SCC
345	5-10,426-427, 419, 605, 611, 473, 952, 426, 428	12/26/06	SCC
348	586,590,592	12/26/06	SCC
358	3.24,462	12/26/06	SCC
324	309	12/26/06	SCC
355	40	12/26/07	SCC
367	50	12/26/06	SCC
382	154, 270	12/3/07	SCC
396	60,89	"	"
345	419	"	"
ABOVE SEARCH UP-DATE.		"	"

SEARCH NOTES		
Search Notes	Date	Examiner
EAST,US-PGPUB,USPAT,EPO,JPO,DERWENT,IBM-TDB.	12/26/06	SCC
INVENTOR NAME SEARCH.	12/26/06	SCC
382/152,154, 254,285,312,252,270.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.	12/3/07	SCC
345/419, 605, 611, 473, 952,426, 428.CCLS.	12/3/07	SCC
"		
396/ 60,89, 213,275.CCLS.	12/3/07	SCC
"		
INTERFERENCE SEARCH , SEE SEARCH HISTORY PRINT OUT.	"	"
SEARCH IEEE OR INSPEC DATA BASE.	"	"
ABOVE SEARCH UP- DATE,	12/3/07	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	154,270	12/3/07	SCC
396	60,89	"	"
345	419	"	"